

<b>Notice of References Cited</b>	Application/Control No. 10/525,374		Applicant(s)/Patent Under Reexamination ETOU ET AL.	
	Examiner Rachel L. Zhang (Burney)		Art Unit 1795	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0053155 A1	03-2004	Emoto et al.	430/137.15
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	M	US-			

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	N	WO 02/056116	07-2002		Emoto S et al.	
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#### NON-PATENT DOCUMENTS

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